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Patent Number(s): US2012120231-A1; JP2012122981-A

Title: Electromagnetic wave imaging apparatus using two electromagnetic waves, has optical component that compensates phase shifting between pulse plane detecting electromagnetic wave and pulse plane probe wave

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Abstract: NOVELTY - The apparatus has a primary or secondary optical system that includes a compensating optical component. The optical component partitions a beam cross section the detecting electromagnetic wave or probe wave (2) into several unit areas. The optical component compensates a phase shifting between the pulse plane the detecting electromagnetic wave and pulse plane the probe wave at several positions in a crossing direction a surface the electro optical crystal (3) and virtual plane.

USE - Electromagnetic wave imaging apparatus e.g. digital camera using two electromagnetic waves.

ADVANTAGE - The spectrum resolution is improved by prolonging the measurable time width the terahertz wave.

DESCRIPTION DRAWING(S) - The drawing shows a schematic cross sectional view illustrating a terahertz wave imaging apparatus.

Probe wave (2)

Electro optical crystal (3)

Polarizer (4)

Analyzer (5)

Measurement target (8)

Drawing:

Derwent Class Code(s): W04 (Audio/Video ing and Systems)

Derwent Manual Code(s): W04-M01B

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